



Data Sheet

#### September 2013

## N-Channel Power MOSFET 50V, 14A, 100 mΩ

These are N-channel power MOSFETs manufactured using the MegaFET process. This process, which uses feature sizes approaching those of LSI integrated circuits, gives optimum utilization of silicon, resulting in outstanding performance. They were designed for use in applications such as switching regulators, switching converters, motor drivers and relay drivers. These transistors can be operated directly from integrated circuits.

Formerly developmental type TA09770.

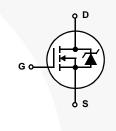
## **Ordering Information**

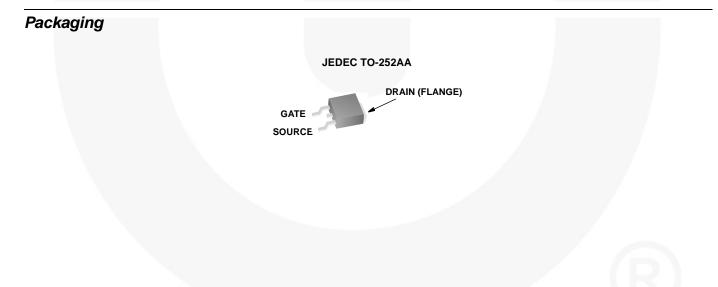
PART NUMBER	PACKAGE	BRAND		
RFD14N05SM9A	TO-252AA	F14N05		

### Features

- 14A, 50V
- r<sub>DS(ON)</sub> = 0.100Ω
- Temperature Compensating PSPICE<sup>®</sup> Model
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- 175<sup>0</sup>C Operating Temperature
- Related Literature
  - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

## Symbol





#### Absolute Maximum Ratings T<sub>C</sub> = 25<sup>o</sup>C, Unless Otherwise Specified

	RFD14N05SM9A	UNITS
Drain to Source Voltage (Note 1)V <sub>DSS</sub>	50	V
Drain to Gate Voltage ( $R_{GS} = 20k\Omega$ ) (Note 1) $V_{DGR}$	50	V
Gate to Source Voltage	±20	V
Continuous Drain CurrentI <sub>D</sub>	14	А
Pulsed Drain Current (Note 3)	Refer to Peak Current Curve	
Pulsed Avalanche Rating E <sub>AS</sub>	Refer to UIS Curve	
Power Dissipation	48	W
Derate above 25 <sup>o</sup> C	0.32	W/ <sup>o</sup> C
Operating and Storage Temperature	-55 to 175	°C
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s	300	°C
Package Body for 10s, See Techbrief 334	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1.  $T_J = 25^{\circ}C$  to  $150^{\circ}C$ .

PARAMETER	SYMBOL	TEST CON	NDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V (Figure 9)		50	-	-	V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250μA		2	-	4	V
Zero Gate Voltage Drain Current	IDSS	$V_{DS}$ = Rated $BV_{DSS}$ , $V_{GS}$ = 0V $V_{DS}$ = 0.8 x Rated $BV_{DSS}$ , $V_{GS}$ = 0V, $T_C$ = 150°C		-	-	25	μA
				-	-	250	μA
Gate to Source Leakage Current	I <sub>GSS</sub>	$V_{GS} = \pm 20V$		-	-	±100	nA
Drain to Source On Resistance (Note 2)	rDS(ON)	I <sub>D</sub> = 14A, V <sub>GS</sub> = 10V, (Fi	gure 11)	-	-	0.100	Ω
Turn-On Time	ton	$V_{DD} = 25V, I_D \approx 14A, V_{GS} = 10V,$ $R_{GS} = 25\Omega, R_L = 1.7\Omega$ (Figure 13)		-	-	60	ns
Turn-On Delay Time	t <sub>d(ON)</sub>			-	14	-	ns
Rise Time	tr			-	26	-	ns
Turn-Off Delay Time	<sup>t</sup> d(OFF)			-	45	-	ns
Fall Time	t <sub>f</sub>			-	17	-	ns
Turn-Off Time	tOFF			-	-	100	ns
Total Gate Charge	Q <sub>g(TOT)</sub>	$V_{GS} = 0V$ to 20V	$V_{DD} = 40V, I_D = 14A,$	-	-	40	nC
Gate Charge at 5V	Q <sub>g(10)</sub>	$V_{GS} = 0V$ to 10V	$R_L = 2.86\Omega$	-	-	25	nC
Threshold Gate Charge	Q <sub>g(TH)</sub>	$V_{GS} = 0V$ to 2V	_ I <sub>g(REF)</sub> = 0.4mA (Figure 13)	-	-	1.5	nC
nput Capacitance $C_{ISS}$ $V_{DS} = 25V, V_{GS} = 0V, f = 1MHz$		-	570	· -	pF		
Output Capacitance	C <sub>OSS</sub>	(Figure 12)		-	185	-	pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			-	50	-	pF
Thermal Resistance Junction to Case	R <sub>θJC</sub>			-	-	3.125	°C/W
Thermal Resistance Junction to Ambient	R <sub>θJA</sub>			-	-	100	°C/W

#### **Electrical Specifications** T<sub>C</sub> = 25<sup>o</sup>C, Unless Otherwise Specified

#### Source to Drain Diode Specifications

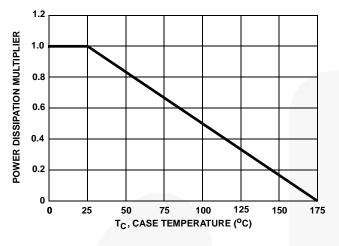
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage (Note 2)	V <sub>SD</sub>	I <sub>SD</sub> = 14A	-	-	1.5	V
Diode Reverse Recovery Time	t <sub>rr</sub>	$I_{SD}$ = 14A, dI <sub>SD</sub> /dt = 100A/µs	-	-	125	ns

NOTES:

2. Pulse Test: Pulse Width ≤300ms, Duty Cycle ≤2%.

3. Repetitive Rating: Pulse Width limited by max junction temperature. See Transient Thermal Impedance Curve (Figure 3) and Peak Current Capability Curve (Figure 5).

#### Typical Performance Curves Unless Otherwise Specified





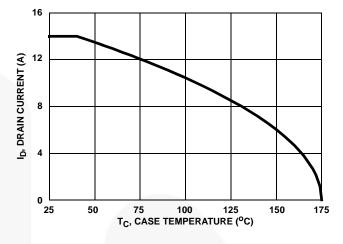
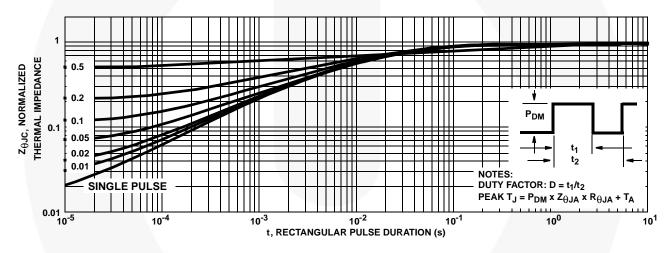
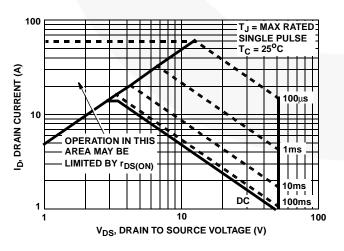


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE









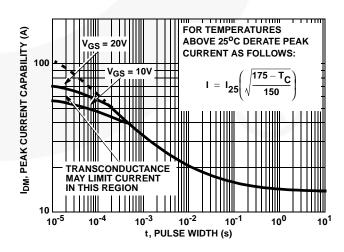
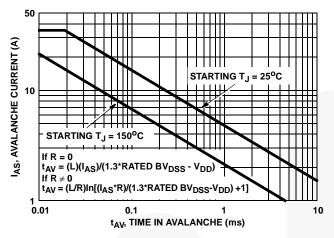


FIGURE 5. PEAK CURRENT CAPABILITY

### Typical Performance Curves Unless Otherwise Specified (Continued)





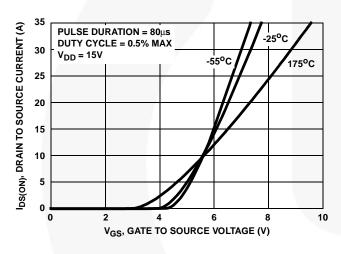
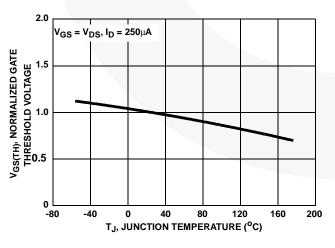
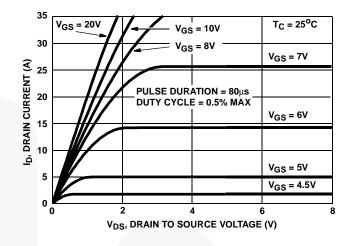


FIGURE 8. TRANSFER CHARACTERISTICS









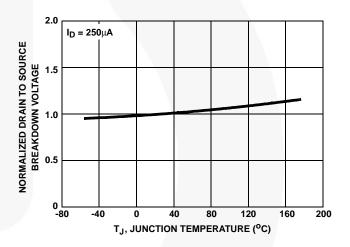


FIGURE 9. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

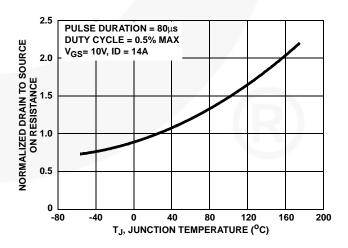


FIGURE 11. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

## Typical Performance Curves Unless Otherwise Specified (Continued)

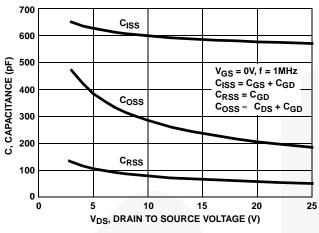
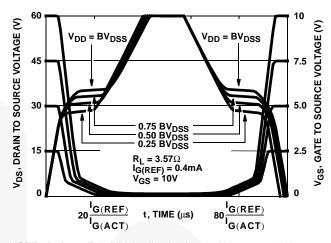


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260, FIGURE 13. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT CURRENT GATE DRIVE



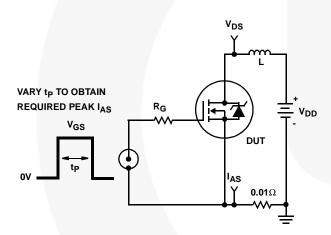


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

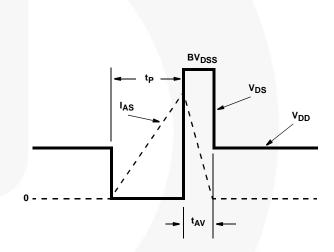


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

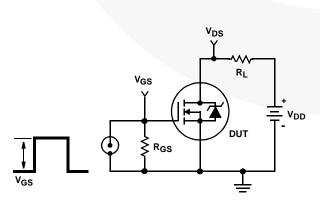


FIGURE 16. SWITCHING TIME TEST CIRCUIT

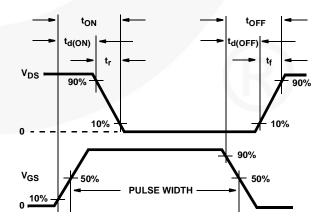


FIGURE 17. RESISTIVE SWITCHING WAVEFORMS

# Test Circuits and Waveforms (Continued)

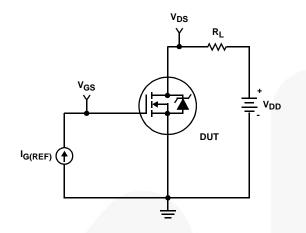
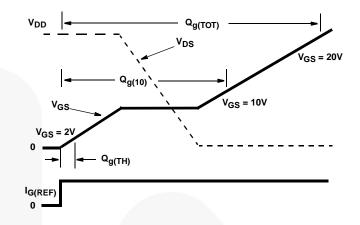


FIGURE 18. GATE CHARGE TEST CIRCUIT

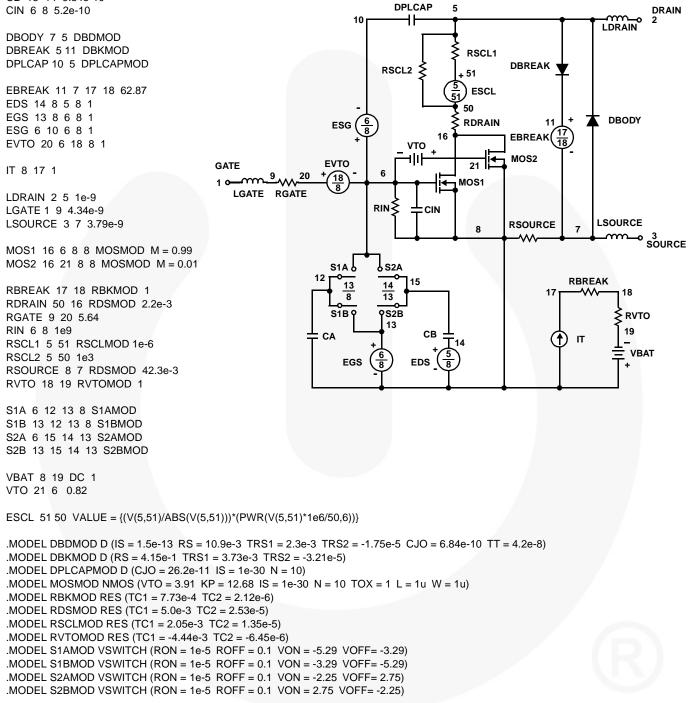




#### **PSPICE Electrical Model**

.SUBCKT RFD14N05 2 1 3 ; rev 9/12/94

CA 12 8 8.84e-10 CB 15 14 9.34e-10 CIN 6 8 5.2e-10



.ENDS

NOTE: For further discussion of the PSPICE model, consult **A New PSPICE Sub-circuit for the Power MOSFET Featuring Global Temperature Options**; written by William J. Hepp and C. Frank Wheatley.



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